

Notice of References Cited

Application/Control No.

10/585,655

Applicant(s)/Patent Under

Reexamination

TAKUMAI ET AL.

Examiner

DEVONA E. FAULK

Art Unit

2615

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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